Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | PARK ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0027259	03-2002	Ikemasu et al.	257/499
	В	US-2002/0030222	03-2002	Agarwal, Vishnu K.	257/310
	С	US-2002/0034877	03-2002	Shin et al.	438/694
	D	US-5,817,562	10-1998	Chang et al.	438/305
	Е	US-6,403,413	06-2002	Hayano et al.	438/238
	F	US-2001/0045589	11-2001	Takeda et al.	257/297
	G	US-2001/0041406	11-2001	Goebel et al.	438/255
	Н	US-			
	1	US-			
	J	US-			
	к	US-			·
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					·
	R		,			
	ŗS					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.